

System-Side Impedance Track™ Fuel Gauge With Integrated Sense Resistor

Check for Samples: bq27421-G1

FEATURES

- Single Series Cell Li-Ion Battery Fuel Gauge
 - Resides on System Board
 - Supports Embedded or Removable Batteries
 - Powered Directly from Battery with Integrated LDO
 - Low-value Integrated Sense Resistor (7 mΩ Typical)
- Easy to Configure Fuel Gauging Based on Patented Impedance Track™ Technology
 - Reports Remaining Capacity and State of Charge (SOC) with Smoothing Filter
 - Automatically Adjusts for Battery Aging, Self-discharge, Temperature, and Rate Changes
 - Battery State of Health (aging) Estimation
- Microcontroller Peripheral Supports:
 - 400-kHz I²C™ Serial Interface
 - Configurable SOC Interrupt, or Battery Low Digital Output Warning
 - Internal Temperature Sensor, or Host Reported Temperature
- 9-pin 1,62 mm × 1,58 mm × 0,5 mm Pitch CSP Package

APPLICATIONS

- Smartphones, Feature phones and Tablets
- Digital Still and Video Cameras
- Handheld Terminals
- MP3 or Multimedia Players

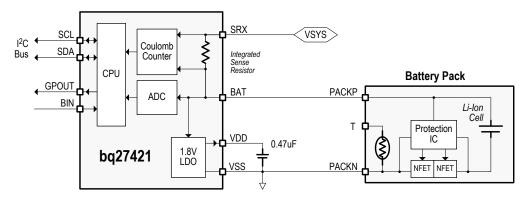
DESCRIPTION

The Texas Instruments bq27421-G1 is an easy to configure microcontroller peripheral that provides system-side fuel gauging for single-cell Li-lon batteries. The device requires minimal user configuration and system microcontroller firmware development.

The bq27421-G1 uses the patented Impedance Track[™] algorithm for fuel gauging, and provides information such as remaining battery capacity (mAh), state-of-charge (%), and battery voltage (mV).

Battery fuel gauging with the bq27421-G1 requires connections only to PACK+ (P+) and PACK- (P-) for a removable battery pack or embedded battery circuit. The tiny 9-pin 1,62 \times 1,58 mm \times 0,5 mm pitch CSP package is ideal for space constrained applications.

TYPICAL APPLICATION



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

Impedance Track is a trademark of Texas Instruments. I²C is a trademark of NXP B.V. Corp Netherlands.



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

DEVICE INFORMATION

AVAILABLE OPTIONS

| PART NUMBER | BATTERY TYPE | CHEM_ID | FIRMWARE VERSION | PACKAGE | T _A | COMM. FORMAT | TAPE and REEL QUANTITY |
|-----------------|---------------------------------------|---------|---------------------|---------|----------------|------------------|------------------------|
| bq27421YZFR-G1A | LiCoO ₂ (4.2 V max charge) | 0.420 | | | | | 3000 |
| bq27421YZFT-G1A | | 0x128 | 1.08 | 000.0 | −40°C to | I ² C | 250 |
| bq27421YZFR-G1B | | 0.212 | (0x0108) | CSP-9 | 85°C | 10 | 3000 |
| bq27421YZFT-G1B | (4.3 - 4.35 V max charge) | 0x312 | | | | | 250 |

- See the CHEM_ID subcommand to confirm the battery chemistry type. See the FW_VERSION subcommand to confirm the firmware version.
- For the most current package and ordering information see the Package Option Addendum at the end of this document; or, see the TI website at www.ti.com.

THERMAL INFORMATION

| | THERMAL METRIC(1) | bq27421-G1 | LIMITO |
|------------------|--|-------------|--------|
| | HERMAL METRIC | YZF(9 PINS) | UNITS |
| θ_{JA} | Junction-to-ambient thermal resistance | 107.8 | |
| θ_{JCtop} | Junction-to-case (top) thermal resistance | 0.7 | |
| θ_{JB} | Junction-to-board thermal resistance | 60.4 | °C/W |
| ΨЈТ | Junction-to-top characterization parameter | 3.5 | C/VV |
| ΨЈВ | Junction-to-board characterization parameter | 60.4 | |
| θ_{JCbot} | Junction-to-case (bottom) thermal resistance | n/a | |

(1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953

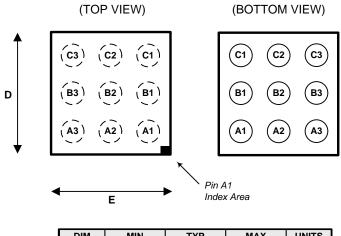
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TRUMENTS



PIN DIAGRAM AND PACKAGE DIMENSIONS



| DIM | MIN | TYP | MAX | UNITS |
|-----|------|------|------|-------|
| D | 1550 | 1580 | 1610 | um |
| Е | 1590 | 1620 | 1650 | μm |

PIN FUNCTIONS

| PIN | 1 | | |
|--|------------|---|---|
| NAME | NO. | TYPE ⁽¹⁾ | DESCRIPTION |
| BAT | С3 | PI, AI | LDO regulator input, battery voltage input, and coulomb counter input typically connected to the PACK+ terminal. |
| VDD | В3 | PO | 1.8V Regulator Output. Decouple with 0.47μF ceramic capacitor to Vss. This pin is not intended to provide power for other devices in the system. |
| WSS R2 C1 PI may be used as a bridge to connect to the board ground plane without requiring a via under the device | | Ground pins. The center pin B2 is the actual device ground pin while pin C1 is floating internally and therefore C1 may be used as a bridge to connect to the board ground plane without requiring a via under the device package. Recommend routing the center pin B2 to the corner pin C1 using a top-layer metal trace on the board. Then route the corner pin C1 to the board ground plane. | |
| SRX | C2 | Al | Integrated high-side sense resistor and coulomb counter input typically connected to system power rail VSYS. |
| GPOUT | A1 | DO | General Purpose open-drain output. May be configured as a Battery Low indicator or perform SOC interrupt (SOC_INT) function. |
| SDA | A2 | DIO | Slave I ² C serial bus for communication with system (Master). Open-drain pins. Use with external 10kΩ pull-up |
| SCL | SCL A3 DIO | | resistors (typical) for each pin. If the external pull-up resistors will be disconnected from these pins during normal operation, recommend using external 1MΩ pull-down resistors to VSS at each pin to avoid floating inputs. |
| BIN | B1 | DI | Battery-insertion detection input. A logic high to low transition is detected as a battery insertion event. Recommend using a pull-up resistor >1M Ω (1.8 M Ω typical) to V _{CC} for reduced power consumption. An internal pull-up resistor option is also available. |

(1) I/O = Digital input/output, IA = Analog input, P = Power connection



ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range (unless otherwise noted)(1)

| | PARAMETER | VALUE | UNIT |
|-------------------|--|-------------------------------|------|
| V _{BAT} | BAT pin input voltage range | -0.3 to 6.0 | V |
| V _{SRX} | SRX pin input voltage range ⁽¹⁾ | V _{BAT} ± 0.03 | V |
| V_{DD} | VDD pin supply voltage range (LDO ouptut) | -0.3 to 2.0 | V |
| V _{IOD} | Open-drain I/O pins (SDA, SCL, GPOUT) | -0.3 to 6.0 | V |
| V _{IOPP} | Push-Pull I/O pins (BIN) | −0.3 to V _{DD} + 0.3 | V |
| T _A | Operating free-air temperature range | -40 to 85 | °C |
| T _{STG} | Storage temperature range | -65 to 150 | °C |

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

RECOMMENDED OPERATING CONDITIONS

 $T_A = 30$ °C and $V_{REGIN} = V_{BAT} = 3.6V$ (unless otherwise noted)

| | PARAMETER | TEST CONDITIONS | MIN | TYP MAX | UNIT |
|---------------------------------|--|---|------|---------|------|
| C _{BAT} ⁽¹⁾ | External input capacitor for internal LDO between BAT and $V_{\rm SS}$ | Nominal capacitor values specified. Recommend a 5% ceramic X5R type | | 0.1 | μF |
| C _{LDO18} (1) | External output capacitor for internal LDO between V_{CC} and V_{SS} | capacitor located close to the device. | | 0.47 | μF |
| V _{PU} (1) | External pull-up voltage for open- drain pins (SDA, SCL, GPOUT) | | 1.62 | 3.6 | V |

⁽¹⁾ Specified by design. Not production tested.

SUPPLY CURRENT

 $T_A = 30$ °C and $V_{REGIN} = V_{BAT} = 3.6V$ (unless otherwise noted)

| | PARAMETER | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|---------------------------------|------------------------|--|-----|-----|-----|------|
| I _{CC} (1) | NORMAL mode current | I _{LOAD} > Sleep Current (2) | | 93 | | μΑ |
| I _{SLP} (1) | SLEEP mode current | I _{LOAD} < Sleep Current (2) | | 21 | | μΑ |
| I _{HIB} ⁽¹⁾ | HIBERNATE mode current | I _{LOAD} < Hibernate Current (2) | | 9 | | μΑ |
| I _{SD} (1) | SHUTDOWN mode current | Fuel gauge in host commanded SHUTDOWN mode. (LDO Regulator Output Disabled.) | | 0.6 | | μΑ |

⁽¹⁾ Specified by design. Not production tested.

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STRUMENTS

⁽²⁾ Wake Comparator Disabled.



DIGITAL INPUT AND OUTPUT DC CHARACTERISTICS

 $T_A = -40$ °C to 85°C, typical values at $T_A = 30$ °C and $V_{REGIN} = 3.6$ V (unless otherwise noted)

| | PARAMETER | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|---------------------|----------------------------------|---|-----------------------|-----|-----|------|
| V _{IH(OD)} | Input voltage, high (2) | External pullup resistor to V _{PU} | V _{PU} * 0.7 | | | V |
| $V_{IH(PP)}$ | Input voltage, high (3) | | 1.4 | | | V |
| V _{IL} | Input voltage, low (2) (3) | | | | 0.6 | V |
| V _{OL} | Output voltage, low (2) | | | | 0.6 | V |
| I _{OH} | Output source current, high (2) | | | | 0.5 | mA |
| I _{OL(OD)} | Output sink current, low (2) | | | | -3 | mA |
| C _{IN} (1) | Input capacitance (2) (3) | | | | 5 | pF |
| I _{lkg} | Input leakage current (I/O pins) | | | | 1 | μΑ |

- Specified by design. Not production tested. Open Drain pins: (SCL, SDA, GPOUT)
- (3) Push Pull pin: (BIN)

LDO REGULATOR, WAKE-UP AND AUTO-SHUTDOWN DC CHARACTERISTICS

 $T_A = -40$ °C to 85°C, typical values at $T_A = 30$ °C and $V_{REGIN} = 3.6$ V (unless otherwise noted)

| | PARAMETER | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|---------------------------------|--|--------------------------------|------|------|-----|------|
| V_{BAT} | BAT pin regulator input | | 2.45 | | 4.5 | V |
| V_{DD} | Regulator output voltage | | | 1.8 | | V |
| UVLO _{IT+} | V _{BAT} Under Voltage Lock Out LDO Wake-Up Rising Threshold ⁽²⁾ | | | 2.0 | | V |
| UVLO _{IT} . | V _{BAT} Under Voltage Lock Out LDO Auto-Shutdown Falling Threshold ⁽²⁾ | | | 1.95 | | V |
| V _{WU+} ⁽¹⁾ | GPOUT (input) LDO Wake-Up rising edge threshold ⁽²⁾ | LDO Wake-up from SHUTDOWN mode | 1.2 | | | V |

- Specified by design. Not production tested. If the device is commanded to SHUTDOWN via I2C with $V_{BAT} > UVLO_{IT+}$, a wake-up rising edge trigger is required on GPOUT .



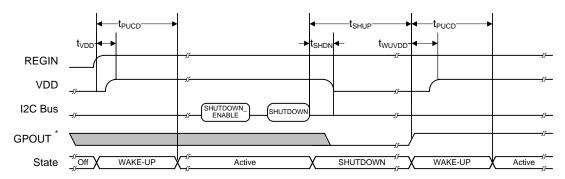
LDO REGULATOR, WAKE-UP AND AUTO-SHUTDOWN AC CHARACTERISTICS

 $T_A = -40$ °C to 85 °C, typical values at $T_A = 30$ °C and $V_{REGIN} = 3.6$ V (unless otherwise noted)

| | PARAMETER | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|----------------------------------|--------------------------------------|--|-----|-----|-----|------|
| t _{SHDN} (1) | SHUTDOWN Entry Time | Time delay from SHUTDOWN command to LDO output disable. | | | 250 | ms |
| t _{SHUP} ⁽¹⁾ | SHUTDOWN GPOUT Low time | Minimum low time of GPOUT (input) in SHUTDOWN before WAKEUP | 10 | | | μs |
| t _{VDD} (1) | Initial V _{DD} Output delay | | | 13 | | ms |
| t _{WUVDD} (1) | Wake-up V _{DD} Output delay | Time delay from rising edge of GPOUT (input) to nominal VDD output. | | 8 | | ms |
| t _{PUCD} | Power-up communication delay | Time delay from rising edge of REGIN to the Active state. Includes firmware initialization time. | | 250 | | ms |

⁽¹⁾ Specified by design. Not production tested.

SHUTDOWN and WAKE-UP Timing



^{*} GPOUT is configured as an input for wake-up signaling.

Figure 1. SHUTDOWN and WAKE-UP Timing Diagram

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RUMENTS



ADC (TEMPERATURE AND CELL MEASUREMENT) CHARACTERISTICS

 $T_A = -40$ °C to 85°C; typical values at $T_A = 30$ °C and $V_{REGIN} = 3.6$ V (unless otherwise noted)

| | PARAMETER | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|-----------------------|------------------------------------|--------------------------|------|-----|-----|------|
| V _{IN(BAT)} | BAT pin voltage measurement range. | Voltage divider enabled. | 2.45 | | 4.5 | V |
| t _{ADC_CONV} | Conversion time | | | 125 | | ms |
| | Effective Resolution | | | 15 | | bits |

⁽¹⁾ Specified by design. Not tested in production.

INTEGRATING ADC (COULOMB COUNTER) CHARACTERISTICS

 $T_A = -40$ °C to 85°C; typical values at $T_A = 30$ °C and $V_{REGIN} = 3.6$ V (unless otherwise noted)

| | PARAMETER | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|----------------------|--|-------------------|-----|----------|-----|------|
| V_{SR} | Input voltage range from BAT to SRX pins | | | BAT ± 25 | | mV |
| t _{SR_CONV} | Conversion time | Single conversion | | 1 | | S |
| | Effective Resolution | Single conversion | | 16 | | bits |

⁽¹⁾ Assured by design. Not tested in production.

INTEGRATED SENSE RESISTOR CHARACTERISTICS

 $T_{\Delta} = -40$ °C to 85°C; typical values at $T_{\Delta} = 30$ °C and $V_{REGIN} = 3.6$ V (unless otherwise noted)

| | PARAMETER | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|---------------------------------|--|--|-----|-----|------|------|
| SRX _{RES} (2) | Resistance of Integrated Sense Resistor from SRX to VSS. | $T_A = 30$ °C | | 7 | | mΩ |
| I _{SRX} ⁽¹⁾ | Recommended Sense Resistor input current. | Long term RMS, average device utilization. | | | 2000 | mA |
| | | Peak RMS current, 10% device utilization. (3) | | | 2500 | mA |
| | | Peak pulsed current, 250mS max, 1% device utilization. (3) | | | 3500 | mA |

⁽¹⁾ Specified by design. Not tested in production.

⁽²⁾ Firmware compensation applied for temperature coefficient of resistor.

⁽³⁾ Device utilization is the long term usage profile at a specific condition compared to the average condition.



12C-COMPATIBLE INTERFACE COMMUNICATION TIMING CHARACTERISTICS

 $T_A = -40$ °C to 85°C; typical values at $T_A = 30$ °C and $V_{REGIN} = 3.6$ V (unless otherwise noted)

| | PARAMETER | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|-----------------------|--------------------------------------|-------------------------------|------|-----|-----|------|
| Standard M | ode (100 kHz) | | | | | |
| t _{d(STA)} | Start to first falling edge of SCL | | 4.0 | | | μs |
| t _{w(L)} | SCL pulse duration (low) | | 4.7 | | | μs |
| t _{w(H)} | SCL pulse duration (high) | | 4.0 | | | μs |
| t _{su(STA)} | Setup for repeated start | | 4.7 | | | μs |
| t _{su(DAT)} | Data setup time | Host drives SDA | 250 | | | ns |
| t _{h(DAT)} | Data hold time | Host drives SDA | 0 | | | ns |
| t _{su(STOP)} | Setup time for stop | | 4.0 | | | μs |
| t _(BUF) | Bus free time between stop and start | Includes Command Waiting Time | 66 | | | μs |
| t _f | SCL/SDA fall time (1) | | | | 300 | ns |
| t _r | SCL/SDA rise time (1) | | | | 300 | ns |
| f _{SCL} | Clock frequency ⁽²⁾ | | | | 100 | kHz |
| Fast Mode (| (400 kHz) | | | | | |
| t _{d(STA)} | Start to first falling edge of SCL | | 600 | | | ns |
| t _{w(L)} | SCL pulse duration (low) | | 1300 | | | ns |
| t _{w(H)} | SCL pulse duration (high) | | 600 | | | ns |
| t _{su(STA)} | Setup for repeated start | | 600 | | | ns |
| t _{su(DAT)} | Data setup time | Host drives SDA | 100 | | | ns |
| t _{h(DAT)} | Data hold time | Host drives SDA | 0 | | | ns |
| t _{su(STOP)} | Setup time for stop | | 600 | | | ns |
| t _(BUF) | Bus free time between stop and start | Includes Command Waiting Time | 66 | | | μs |
| t _f | SCL/SDA fall time (1) | | | | 300 | ns |
| t _r | SCL/SDA rise time (1) | | | | 300 | ns |
| f _{SCL} | Clock frequency ⁽²⁾ | | | | 400 | kHz |

- (1) Specified by design. Not production tested.
- (1) Opcomined by design. Not production tested.
 (2) If the clock frequency (f_{SCL}) is > 100 kHz, use 1-byte write commands for proper operation. All other transactions types are supported at 400 kHz. (Refer to I²C INTERFACE and I²C Command Waiting Time)

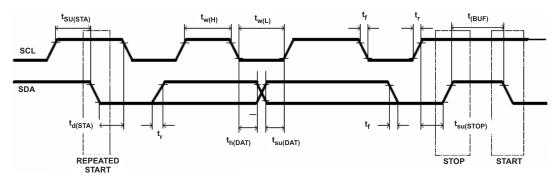


Figure 2. I²C-Compatible Interface Timing Diagrams

GENERAL DESCRIPTION

The bq27421-G1 accurately predicts the battery capacity and other operational characteristics of a single Libased rechargeable cell. It can be interrogated by a system processor to provide cell information, such as stateof-charge (SOC).

Information is accessed through a series of commands, called *Standard Commands*. Further capabilities are provided by the additional *Extended Commands* set. Both sets of commands, indicated by the general format *Command()*, are used to read and write information contained within the bq27421-G1 control and status registers, as well as its data locations. Commands are sent from system to gauge using the bq27421-G1's I²C serial communications engine, and can be executed during application development, system manufacture, or end-equipment operation.

The key to the bq27421-G1's high-accuracy gas gauging prediction is Texas Instrument's proprietary Impedance Track™ algorithm. This algorithm uses cell measurements, characteristics, and properties to create state-of-charge predictions that can achieve high accuracy across a wide variety of operating conditions and over the lifetime of the battery.

The bq27421-G1 measures charge/discharge activity by monitoring the voltage across a small-value sense resistor. When a cell is attached to the bq27421-G1, cell impedance is computed, based on cell current, cell open-circuit voltage (OCV), and cell voltage under loading conditions.

The bq27421-G1 uses an integrated temperature sensor for estimating cell temperature. Alternatively, the host processor can provide temperature data for the bq27421-G1.

To minimize power consumption, the bq27421-G1 has several power modes: INITIALIZATION, NORMAL, SLEEP, HIBERNATE and SHUTDOWN. The bq27421-G1 passes automatically between these modes, depending upon the occurrence of specific events, though a system processor can initiate some of these modes directly. More details are found in the bq27421-G1 Technical Reference Manual (SLUUAC5).

NOTE

Formatting Conventions in this Document:

Commands: *italics* with parentheses() and no breaking spaces, for example, *RemainingCapacity()*.

Data Flash: italics, bold, and breaking spaces, for example, Design Capacity.

Register bits and flags: *italics* with brackets [], for example, [TDA]

Data flash bits: *italics*, bold, and brackets [], for example, [LED1]

Modes and states: ALL CAPITALS, for example, UNSEALED mode.



STANDARD DATA COMMANDS

The bq27421-G1 uses a series of 2-byte standard commands to enable system reading and writing of battery information. Each standard command has an associated command-code pair, as indicated in . Because each command consists of two bytes of data, two consecutive I2C transmissions must be executed both to initiate the command function, and to read or write the corresponding two bytes of data. Additional details are found in the bq27421-G1 Technical Reference Manual (SLUUAC5).

Table 1. Standard Commands

| NAME | | COMMAND CODE | UNITS | SEALED ACCESS |
|----------------------------|-------|-----------------|---------|---------------|
| Control() | CNTL | 0x00 / 0x01 | N/A | R/W |
| Temperature() | TEMP | 0x02 / 0x03 | 0.1°K | R/W |
| Voltage() | VOLT | 0x04 / 0x05 | mV | R |
| Flags() | FLAGS | 0x06 / 0x07 | N/A | R |
| NominalAvailableCapacity() | | 0x08 / 0x09 | mAh | R |
| FullAvailableCapacity() | | 0x0a / 0x0b | mAh | R |
| RemainingCapacity() | RM | 0x0c / 0x0d | mAh | R |
| FullChargeCapacity() | FCC | 0x0e / 0x0f | mAh | R |
| AverageCurrent() | | 0x10 / 0x11 | mA | R |
| StandbyCurrent() | | 0x12 / 0x13 | mA | R |
| MaxLoadCurrent() | | 0x14 / 0x15 | mA | R |
| AveragePower() | | 0x18 / 0x19 | mW | R |
| StateOfCharge() | SOC | 0x1c / 0x1d | % | R |
| IntTemperature() | | 0x1e / 0x1f | 0.1°K | R |
| StateOfHealth() | SOH | 0x20 / 0x21 | num / % | R |

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NSTRUMENTS



Control(): 0x00/0x01

Issuing a *Control()* command requires a subsequent 2-byte subcommand. These additional bytes specify the particular control function desired. The *Control()* command allows the system to control specific features of the bq27421-G1 during normal operation and additional features when the device is in different access modes, as described in . Additional details are found in the *bq27421-G1 Technical Reference Manual (SLUUAC5)*.

Table 2. Control() Subcommands

| CNTL FUNCTION | CNTL DATA | SEALED ACCESS | DESCRIPTION |
|-----------------|-----------|---------------|--|
| CONTROL_STATUS | 0x0000 | Yes | Reports the status of device. |
| DEVICE_TYPE | 0x0001 | Yes | Reports the device type (0x0421). |
| FW_VERSION | 0x0002 | Yes | Reports the firmware version of the device. |
| DM_CODE | 0x0004 | Yes | Reports the Data Memory Code number stored in NVM. |
| PREV_MACWRITE | 0x0007 | Yes | Returns previous MAC command code. |
| CHEM_ID | 0x0008 | Yes | Reports the chemical identifier of the Impedance Track™ configuration |
| BAT_INSERT | 0x000c | Yes | Forces the [BAT_DET] bit set when the [BIE] bit is 0. |
| BAT_REMOVE | 0x000d | Yes | Forces the [BAT_DET] bit clear when the [BIE] bit is 0. |
| SET_HIBERNATE | 0x0011 | Yes | Forces CONTROL_STATUS [HIBERNATE] to 1. |
| CLEAR_HIBERNATE | 0x0012 | Yes | Forces CONTROL_STATUS [HIBERNATE] to 0. |
| SET_CFGUPDATE | 0x0013 | No | Force CONTROL_STATUS [CFGUPMODE] to 1 and gauge enters CONFIG UPDATE mode. |
| SHUTDOWN_ENABLE | 0x001b | No | Enables device SHUTDOWN mode. |
| SHUTDOWN | 0x001c | No | Commands the device to enter SHUTDOWN mode. |
| TOGGLE_GPOUT | 0x0023 | Yes | Commands the device to toggle the GPOUT pin for 1ms. |
| SEALED | 0x0020 | No | Places the device in SEALED access mode. |
| RESET | 0x0041 | No | Performs a full device reset. |
| SOFT_RESET | 0x0042 | No | Gauge exits CONFIG UPDATE mode. |

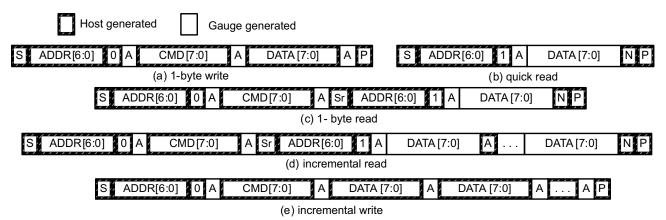
Refer to the bq27421-G1 Technical Reference Manual for detailed descriptions for the Standard Data Commands and *Control()* subcommands.



FUNCTIONAL DESCRIPTION

I²C INTERFACE

The bg27421-G1 supports the standard I²C read, incremental read, quick read, one-byte write, and incremental write functions. The 7-bit device address (ADDR) is the most significant 7 bits of the hex address and is fixed as 1010101. The first 8 bits of the I²C protocol are, therefore, 0xAA or 0xAB for write or read, respectively.

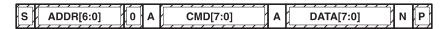


(S = Start, Sr = Repeated Start, A = Acknowledge, N = No Acknowledge, and P = Stop).

The quick read returns data at the address indicated by the address pointer. The address pointer, a register internal to the I²C communication engine, increments whenever data is acknowledged by the bg27421-G1 or the I²C master. "Quick writes" function in the same manner and are a convenient means of sending multiple bytes to consecutive command locations (such as two-byte commands that require two bytes of data).

The following command sequences are not supported:

Attempt to write a read-only address (NACK after data sent by master):



Attempt to read an address above 0x6B (NACK command):



I²C Time Out

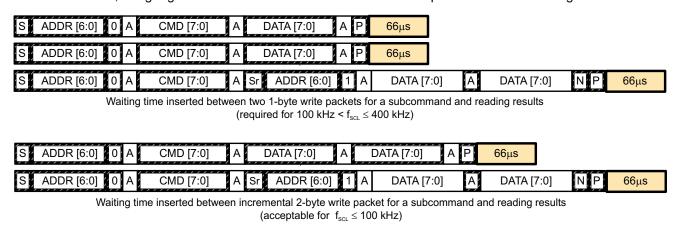
The I²C engine releases both SDA and SCL if the I²C bus is held low for 2 seconds. If the bq27421-G1 is holding the lines, releasing them frees them for the master to drive the lines. If an external condition is holding either of the lines low, the I²C engine enters the low-power sleep mode.

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I²C Command Waiting Time

To ensure proper operation at 400 kHz, a $t_{(BUF)} \ge 66 \mu s$ bus-free waiting time must be inserted between all packets addressed to the bq27421-G1. In addition, if the SCL clock frequency (f_{SCL}) is > 100 kHz, use individual 1-byte write commands for proper data flow control. The following diagram shows the standard waiting time required between issuing the control subcommand the reading the status result. For read-write standard command, a minimum of 2 seconds is required to get the result updated. For read-only standard commands, there is no waiting time required, but the host must not issue any standard command more than two times per second. Otherwise, the gauge could result in a reset issue due to the expiration of the watchdog timer.





Waiting time inserted after incremental read

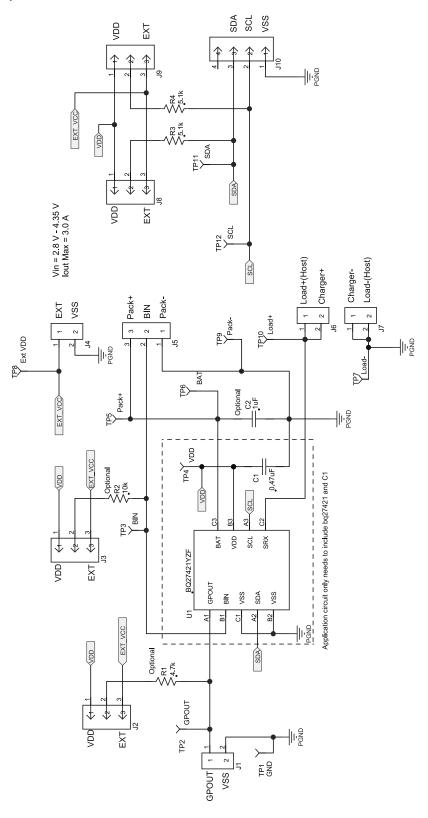
I²C Clock Stretching

A clock stretch can occur during all modes of fuel gauge operation. In SLEEP and HIBERNATE modes, a short \leq 100 µs clock stretch occurs on all I²C traffic as the device must wake-up to process the packet. In the other modes (INITIALIZATION, NORMAL) a \leq 4 ms clock stretching period may occur within packets addressed for the fuel gauge as the I²C interface performs normal data flow control.

Submit Documentation Feedback

TEXAS INSTRUMENTS

REFERENCE (EVM) SCHEMATIC







1-Aug-2013

PACKAGING INFORMATION

| Orderable Device | Status | Package Type | _ | Pins | _ | Eco Plan | Lead/Ball Finish | MSL Peak Temp | Op Temp (°C) | Device Marking | Samples |
|------------------|--------|--------------|---------|------|------|----------------------------|------------------|--------------------|--------------|----------------|---------|
| | (1) | | Drawing | | Qty | (2) | | (3) | | (4/5) | |
| BQ27421YZFR-G1A | ACTIVE | DSBGA | YZF | 9 | 3000 | Green (RoHS & no Sb/Br) | SNAGCU | Level-1-260C-UNLIM | -40 to 85 | BQ27421 G1A | Samples |
| BQ27421YZFR-G1B | ACTIVE | DSBGA | YZF | 9 | 3000 | Green (RoHS & no Sb/Br) | SNAGCU | Level-1-260C-UNLIM | -40 to 85 | BQ27421 G1B | Samples |
| BQ27421YZFT-G1A | ACTIVE | DSBGA | YZF | 9 | 250 | Green (RoHS & no Sb/Br) | SNAGCU | Level-1-260C-UNLIM | -40 to 85 | BQ27421 G1A | Samples |
| BQ27421YZFT-G1B | ACTIVE | DSBGA | YZF | 9 | 250 | Green (RoHS & no Sb/Br) | SNAGCU | Level-1-260C-UNLIM | -40 to 85 | BQ27421 G1B | Samples |

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

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PACKAGE OPTION ADDENDUM

1-Aug-2013

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PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





| | Dimension designed to accommodate the component width |
|----|---|
| B0 | Dimension designed to accommodate the component length |
| K0 | Dimension designed to accommodate the component thickness |
| W | Overall width of the carrier tape |
| P1 | Pitch between successive cavity centers |

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

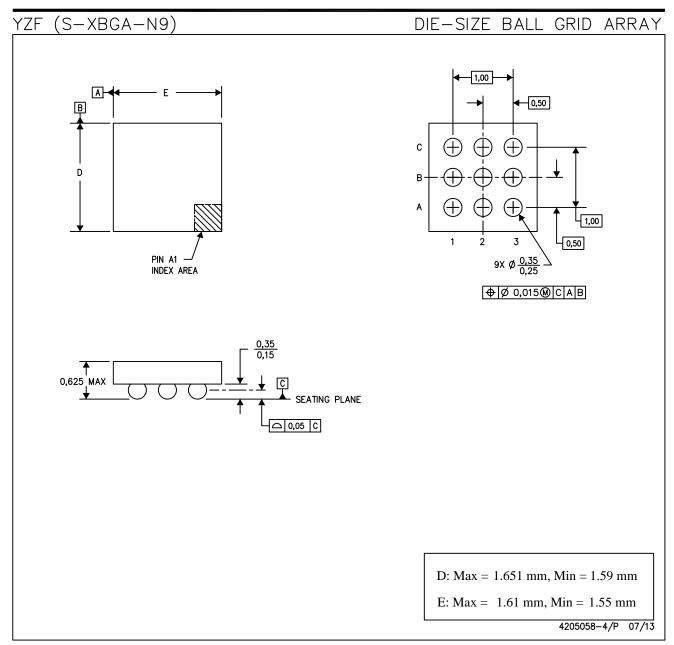
| Device | Package Type | Package Drawing | | | Reel Diameter (mm) | Reel Width W1 (mm) | A0 (mm) | B0 (mm) | K0 (mm) | P1 (mm) | W (mm) | Pin1 Quadrant |
|-----------------|-----------------|--------------------|---|------|--------------------------|--------------------------|------------|------------|------------|------------|-----------|------------------|
| BQ27421YZFR-G1B | DSBGA | YZF | 9 | 3000 | 180.0 | 8.4 | 1.78 | 1.78 | 0.69 | 4.0 | 8.0 | Q1 |
| BQ27421YZFT-G1A | DSBGA | YZF | 9 | 250 | 180.0 | 8.4 | 1.78 | 1.78 | 0.69 | 4.0 | 8.0 | Q1 |

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*All dimensions are nominal

| Device | Package Type | Package Drawing | Pins | SPQ | Length (mm) | Width (mm) | Height (mm) |
|-----------------|--------------|-----------------|------|------|-------------|------------|-------------|
| BQ27421YZFR-G1B | DSBGA | YZF | 9 | 3000 | 182.0 | 182.0 | 17.0 |
| BQ27421YZFT-G1A | DSBGA | YZF | 9 | 250 | 182.0 | 182.0 | 17.0 |



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. NanoFree™ package configuration.

NanoFree is a trademark of Texas Instruments.



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